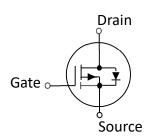


30V P-Channel MOSFET

SYMBOL

- Advanced Trench Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking



Electric	Electrical Characteristics in C/P Test (TJ at 25 °C)					
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V _{(BR)DSS}	Drain-Source Breakdown Voltage	-30		_	V	V _{GS} =0V, I _D =-250µA
R _{DS(ON)}	Static Drain-Source On-Resistance	_	10	13	mΩ	V _{GS} =10V, I _D =-1A(2)
R _{DS(ON)}	Static Drain-Source On-Resistance		15.7	20	mΩ	V _{GS} =4.5V, I _D =-1A(2)
$V_{GS(th)}$	Gate Threshold Voltage	-1.2		-2.5	V	V_{DS} = V_{GS} , I_D =-250 μ A
I _{DSS}	Drain-to-Source Leakage Current	_	_	-1	μA	V _{DS} =-30V, V _{GS} =0V
I _{GSS}	Gate-to-Source Leakage Current	-100	_	100	nA	V _{DS} =0V, V _{GS} =±20V
T _J , T _{STG}	Operating and Storage Temperature	-55°C to 150°C Max.				

Mechanical Data	Die Drawing				
Chip Size	1719 µm X 1180 µm	1180.2 um			
Gate Pad Size	150 µm X 150 µm				
Source Pad Size	1508 µm X 980 µm	1508 um			
Scribe Line Width	60 µm				
Wafer Thickness	150 µm				
Wafer Diameter	200 mm	17194 um			
Gross Die	13104 EA				
Source Metallization	Al-Cu (4µm typical)	980.2 um			
Drain Metallization	Ti-Ni-Ag	730.2 um			
Passivation	SiN	150 um			
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C				

(1) This characteristic assumes the die is assembled in SOP-8 package. Actual performance may degrade when assembled.

-1-

(2) Pulse Width tp = < 1 mS, Duty Cycle < 2%.



Specific Assembly Information Bill of Material (BOM)		Die Drawing		
Package Type	DFN5*6	1180.2 um		
Die Attach Method	Soft solder	1508 um		
Soft Solder Composition	Pb,Sn,Ag			
Gate Wire Bonding	Cu, 2 mil x1	1719.4 um		
Source Wire Bonding	Cu, 2 mil x8	980.2 um		
Molding Compound Manufacturer	G700HF	730.2 um		
Solder Plating Composition	Pure Tin			

Position			Bonding Diagram Top View
	X (um)	Y (um)	
ZERO	0	0	тор
ТОР	1719.4	1180.2	53
S1	100	100	
S2	1358	350	52
S3	1608	1080.2	51 62
G1	1541.55	31.15	ZERO
G2	1691.55	181.15	



Electrical Characteristics in F/T Test (TJ at 25 °C)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I _{DSS}	Drain-to-Source Leakage Current	_		-1	μA	V _{DS} =-30V, V _{GS} =0V
I _{GSSF}	Gate-to-Source Leakage Current	_	_	100	nA	V _{DS} =0V, V _{GS} =+20V
I _{GSSR}	Gate-to-Source Leakage Current	_	—	-100	nA	V _{DS} =0V, V _{GS} =-20V
BV _{DSS}	Drain-Source Breakdown Voltage	-30	—	_	V	V _{GS} =0V, I _D =-250µA
BV_{DSS}	Drain-Source Breakdown Voltage	-30	—	_	V	V _{GS} =0V, I _D =-1mA
R _{DS(ON)}	Static Drain-Source On-Resistance	_	_	15	mΩ	V _{GS} =-10V, I _D =-8A
R _{DS(ON)}	Static Drain-Source On-Resistance	_	—	25	mΩ	V _{GS} =-4.5V, I _D =-6A
$V_{GS(th)}$	Gate Threshold Voltage	-1.2	—	-2.5	V	V_{DS} =V _{GS} , I _D =-250µA
V_{SD}	Body Diode Forward Voltage	—	—	-1.2	V	V _{GS} =0V, I _{SD} =-8A
I _{AS}	Avalanche Current				А	V_{DD} =25V, V_{GS} =10V, R_{G} =25 Ω , L=0.5mH
T _J , T _{STG}	Operating and Storage Temperature	-55	_	150	°C	



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